



Dr. Manmohan Singh, Prime Minister of India is presenting the National Award for Quality Products in Instrumentation to Dr. Anil Jain, President, Vaiseshika Electron Devices at the Vigyan Bhavan, New Delhi on 30th August 2004.



National Award Certificate

Vaiseshika Electron Devices has been awarded the National Award for Quality Products in Instrumentation for the year 2002 by the Small Industries Development Organisation, Ministry of Small Scale Industries, Government of India, New Delhi. Dr. Manmohan Singh, Prime Minister of India presented the National Award for Quality Products in Instrumentation to Dr. Anil Jain, President, Vaiseshika Electron Devices at the Vigyan Bhavan, New Delhi on 30th August 2004.

Vaiseshika Electron Devices has been manufacturing electronics calibration standards, test and measuring instruments for the last 30 years. Most of the calibration standards produced by the company are import substitutes and employ precious materials like ceramic, gold and platinum to enhance the reliability and accuracy of the instruments.

Vaiseshika has specialized in the manufacturing of resistance calibration standards, temperature, pressure and force standards. The instruments of the company have been used in the most prestigious national defence projects of the country namely **the Light Combat Aircraft, the Jaguar, the Sukhoi and the MIG Aircraft Projects of the Indian Air Force. AGNI Missile and Satellite Launch Programmes of the Indian Space Research Organization. Further the Indian Space Research Organisation and the Hindustan Aeronautics Limited have been using Vaiseshika calibration standards in the Polar Satellite Launch Vehicle Project and the Advance Light Helicopter Project.** The company has been exporting its instruments to Sudan, Ethiopia, Singapore and Malaysia.



Vaiseshika Electron Devices has received a large number of National Awards & Professional Honours in recognition of its outstanding contributions in the field of Electronic Instrumentation, Quality Control, Precision Measurements and Standardization.

1. **Best Instrument Award** at the World Instrumentation Symposium and Trade Exposition (WISITEX 1981) Silver Trophy for Best Instrument Design.
2. **Outstanding Young Entrepreneur Award** by the Scientific Instruments Manufacturers Association in 1984.
3. **Fellow, the Institution of Electronics and Telecommunication Engineers**, New Delhi in 1987.
4. **IMM Bata Silver Trophy for Excellence in Management** by the Indian Institute of Marketing and Management in 1988.
5. **National Award Coverage in the National Newspaper the Tribune**, January 19, 1989.
6. **Kamla Patra Award for Outstanding Entrepreneurship** by the Indian Jaycees in 1990.
7. **Fellowship and Certificate of Attendance** awarded for participation in HET INSTRUMENT 1994 at Utrecht by the Centre for the Promotion of Imports from Developing Countries, Ministry of Foreign Affairs, Government of Netherlands, Rotterdam in 1994.
8. **ISO 9001:2000 Certification** conferred by the STQC Directorate, Department of Information Technology, Government of India, New Delhi having accreditation from the Dutch Council for Accreditation, Utrecht, Netherlands in April 2001.
9. **Haryana State Award** for indigenization and innovation in calibration standards on 15th August 1999.
10. **14th Lal C. Verma Award** conferred by the Institution of Electronics and Telecommunication Engineers for outstanding contributions in Standardization, Quality Control & Precision Measurements during the last ten years in April 2000.
11. **National Award for Quality Products in Process Control Instrumentation** for the year 2002 by the Ministry of Industry, Government of India, New Delhi. Dr. Manmohan Singh, Prime Minister of India conferred this Award on 30th August 2004.
12. **NABL Accredited Metrology Laboratory** approved by the National Accreditation Board for Testing and Calibration Laboratories, Department of Science & Technology, Government of India, New Delhi vide Certificate No. C-0329 dated 09th December 2005.



National Quality Award Trophy